Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/665,469	ONISHI, TOSHIKAZU	
Examiner	Art Unit	
 Phillip Nguyen	2828	

SEARCHED						
Class	Subclass	Date	Examiner			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

ES STRATEGY)
DATE	EXMR
4/21/2006	PN
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